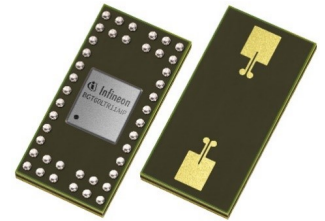


Low power 60 GHz Doppler radar sensor with antennas in package

Features

- 60 GHz transceiver MMIC with one transmitter and one receiver unit
- Antennas in package (AIP) ($6.7 \times 3.3 \times 0.56 \text{ mm}^3$)
- Pulsed Doppler mode of operation for low power consumption
- Autonomous mode
 - Integrated detector for motion and direction of movement
 - Direct output of motion detection signal
 - 15 configurable thresholds for target detection range
 - 16 configurations for detection status hold time
 - 4 configurable operating frequencies
 - 4 configurable pulse repetition rates
- High performance enabled from Infineon's BiCMOS technology
 - Fully integrated low phase noise VCO and PLL
 - Medium power amplifier with configurable output power and integrated power detector
 - Low noise variable gain baseband amplifiers
 - Fully ESD protected device



RoHS



Halogen-free

Potential applications

The BGT60LTR11AIP adds 'smartness' to traditional motion sensing applications and beyond:

- Smart home devices (thermostats, smoke detectors, smart speakers, etc.)
- Smart building (contactless switches, occupancy and proximity sensors, etc.)
- Smart appliances (service robots, washing machine, and kitchen appliances)
- Smart lighting systems and security systems including IP cameras
- Screen based systems (TVs, monitors, laptops, or tablets)

Product validation

Qualified for industrial applications according to the relevant tests of JEDEC47/20/22.

Description

The BGT60LTR11AIP is a fully integrated millimeter wave Doppler motion sensor with antenna in package. The sensor detects the motion as well as the direction of a moving target. It supports the following two operation modes, which can be selected via hardware preset pins:

- Autonomous mode: the sensor configuration parameters, detection threshold and hold time are set via external resistors; the pulse repetition rate and the operation frequency are set via hardware preset pins
- SPI mode: it allows the SPI connection to a microcontroller for more real time sensor configurations, that can be written in the internal registers through SPI

The BGT60LTR11AIP integrates a medium power amplifier with configurable/adjustable output power, which can be controlled via SPI. The transmitted power is monitored by an integrated power detector. The packaged monolithic microwave integrated circuit (MMIC) features integrated broad-beam antennas for maximum area coverage.

Product type	Package	Marking	Ordering code	Description
BGT60LTR11AIP	PG-UF2BGA-42	L11E	BGT60LTR11AIP E6327XUMA2	Operates in the frequency band from 61 GHz to 61.5 GHz
BGT60LTR11BAIP	PG-UF2BGA-42	L11J	BGT60LTR11BAIP XUMA1	Operates in the frequency band from 60.5 GHz to 61 GHz (Japanese ISM band)
BGT60LTR11SAIP	PG-UF2BGA-42	S11E	BGT60LTR11SAIP XUMA1	BGT60LTR11AIP down-specified version with reduced detection range (autonomous mode) and operating temperature from -10 to +70°C

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1 Electrical characteristics

1.1 Absolute maximum ratings

Table 1 Absolute maximum ratings

$T_{OP} = -20^{\circ}\text{C} \dots 85^{\circ}\text{C}$ for BGT60LTR11AIP and BGT60LTR11BAIP; $T_{OP} = -10^{\circ}\text{C} \dots 70^{\circ}\text{C}$ for BGT60LTR11SAIP; all voltages with respect to ground, positive current flowing into pin (unless otherwise specified).

Parameter	Symbol	Values			Unit	Note or Test Condition
		Min.	Typ.	Max.		
Supply voltage	V_{DD}	-0.3	–	1.9	V	
Voltage applied to non-RF I/O pins	$V_{DC,I/O}$	-0.3	–	$V_{DD}+0.3$	V	
Total power dissipation	P_{DISS}	–	–	300	mW	
Storage temperature range	T_{STG}	-40	–	150	$^{\circ}\text{C}$	
Operational temperature range (BGT60LTR11AIP and BGT60LTR11BAIP)	T_{OP}	-20	–	+85	$^{\circ}\text{C}$	Temperature at package soldering point
Operational temperature range (BGT60LTR11SAIP)	T_{OP}	-10	–	+70	$^{\circ}\text{C}$	Temperature at package soldering point
Thermal resistance of package	$R_{th,P}$	–	67	–	K/W	Represents bulk silicon to solder balls

Attention: Stresses above the maximum values listed here may cause permanent damage to the device. Maximum ratings are absolute ratings; exceeding only one of these values may cause irreversible damage to the integrated circuit. Exposure to conditions at or below absolute maximum rating but above the specified maximum operation conditions may affect device reliability and lifetime. Functionality of the device might not be given under these conditions.

1.2 ESD integrity

Table 2 ESD integrity

Parameter	Symbol	Values			Unit	Note or Test Condition
		Min.	Typ.	Max.		
ESD robustness HBM	$V_{ESD-HBM}$	-1	–	1	kV	All pins
ESD robustness CDM	$V_{ESD-CDM}$	-500	–	500	V	All pins

1 Electrical characteristics

1.3 Power supply

Table 3 Power supply electrical characteristics

$T_{OP} = -20^{\circ}\text{C} \dots 85^{\circ}\text{C}$ for BGT60LTR11AIP and BGT60LTR11BAIP; $T_{OP} = -10^{\circ}\text{C} \dots 70^{\circ}\text{C}$ for BGT60LTR11SAIP.

Parameter	Symbol	Values			Unit	Note or Test Condition
		Min.	Typ.	Max.		
Supply voltage	V_{DD}	1.45	1.5	1.6	V	
Current consumption in pulse-on phase	I_{Pulse_ON}	–	128	–	mA	
Current consumption in pulse-off phase	I_{Pulse_OFF}	–	0.8	–	mA	
Pulsed mode average power consumption	$P_{5/2000}$	–	2.3	–	mW	Duty cycle of 5/2000 μs
	$P_{5/1000}$	–	3.4	–	mW	Duty cycle of 5/1000 μs
	$P_{5/500}$	–	5.6	–	mW	Duty cycle of 5/500 μs
	$P_{5/250}$	–	10.3	–	mW	Duty cycle of 5/250 μs

1.4 System parameters

Table 4 System parameters

$T_{OP} = -20^{\circ}\text{C} \dots 85^{\circ}\text{C}$ for BGT60LTR11AIP and BGT60LTR11BAIP; $T_{OP} = -10^{\circ}\text{C} \dots 70^{\circ}\text{C}$ for BGT60LTR11SAIP.

Parameter	Symbol	Values			Unit	Note or Test Condition
		Min.	Typ.	Max.		
Supply voltage	V_{DD}	1.45	1.5	1.6	V	
Transmitted frequency (BGT60LTR11AIP and BGT60LTR11SAIP)	f_{TX}	61	61.25	61.5	GHz	$V_{tune} = V_{CPOUTPLL}$
Transmitted frequency (BGT60LTR11BAIP)	f_{TX_B}	60.5	60.75	61	GHz	$V_{tune} = V_{CPOUTPLL}$
Output power (EIRP ¹⁾)	P_{TX}	–	+10	–	dBm	
Spurious emission < 40 GHz (EIRP)	P_{SPUR1}	–	–	-42	dBm	FCC 15.209
Spurious emission > 40 GHz and < 57 GHz (EIRP)	P_{SPUR2}	–	–	-20	dBm	ETSI EN 305 550
Spurious emission > 64 GHz and < 78 GHz (EIRP)	P_{SPUR3}	–	–	-20	dBm	ETSI EN 305 550
Spurious emission > 78 GHz (EIRP)	P_{SPUR4}	–	–	-30	dBm	ETSI EN 305 550
Frequency drift vs. temperature	$\Delta f/\Delta T$	–	-10	–	MHz/K	$T_{OP} = -20^{\circ}\text{C} \dots +85^{\circ}\text{C}$ $V_{DD} = 1.5\text{ V}$ Free running VCO

1) Equivalent isotropic radiated power.

1.5 PLL parameters

Table 5 PLL parameters

$T_{OP} = -20^{\circ}\text{C} \dots 85^{\circ}\text{C}$ for BGT60LTR11AIP and BGT60LTR11BAIP; $T_{OP} = -10^{\circ}\text{C} \dots 70^{\circ}\text{C}$ for BGT60LTR11SAIP; $V_{DD} = 1.45\text{ V} \dots 1.6\text{ V}$.

Parameter	Symbol	Values			Unit	Note or Test Condition
		Min.	Typ.	Max.		
External crystal frequency	f_{CRY}	–	38.4	–	MHz	
PLL lock frequency (BGT60LTR11AIP and BGT60LTR11SAIP) ¹⁾	f_L	61	–	61.5	GHz	
PLL lock frequency (BGT60LTR11BAIP) ¹⁾	f_{L_B}	60.5	–	61	GHz	

1) Programmed through Reg5 (for more information refer to AN625). Keep a 50 MHz guard band each side from the band edge to avoid outside of ISM band emission.

Warning: *Sensors operating in close vicinity at the same operating frequency can interfere!*

1.6 Frequency divider

Table 6 Frequency divider electrical characteristics

$T_{OP} = -20^{\circ}\text{C} \dots 85^{\circ}\text{C}$ for BGT60LTR11AIP and BGT60LTR11BAIP; $T_{OP} = -10^{\circ}\text{C} \dots 70^{\circ}\text{C}$ for BGT60LTR11SAIP; $V_{DD} = 1.45\text{ V} \dots 1.6\text{ V}$, Freq = 61.25 GHz.

Parameter	Symbol	Values			Unit	Note or Test Condition
		Min.	Typ.	Max.		
Divider output frequency 1	f_{DIV1}	–	9.6	–	MHz	Selectable via SPI (divided by 4 from crystal oscillator)
Dividing factor 2	D_{DIV1}	–	2^{14}	–	–	Selectable via SPI
Dividing factor 3	D_{DIV2}	–	2^{17}	–	–	Selectable via SPI
Dividing factor 4	D_{DIV3}	–	2^{21}	–	–	Selectable via SPI
Divider output voltage range	V_{DIV}	0	–	V_{DD}	V	
External capacitive load	$C_{extLoad}$	–	–	15	pF	

1.7 Antenna characteristics

Table 7 Antenna in package specifications

Parameter	Symbol	Values			Unit	Note or Test Condition
		Min.	Typ.	Max.		
Operating frequency range (BGT60LTR11AIP and BGT60LTR11SAIP)	f_{op}	60.5	–	61.5	GHz	
Transmitter antenna gain	G_{TX}	–	6	–	dBi	@ Freq = 61.25 GHz
Receiver antenna gain	G_{RX}	–	6	–	dBi	@ Freq = 61.25 GHz
Horizontal -6dB beamwidth	H_{-6dBbw}	–	±50	–	deg	@ Freq = 61.25 GHz
Vertical -6dB beamwidth	E_{-6dBbw}	–	±70	–	deg	@ Freq = 61.25 GHz
Horizontal sidelobe level (H-SLL)		–	12	–	dB	@ Freq = 61.25 GHz
Vertical sidelobe level (V-SLL)		–	12	–	dB	@ Freq = 61.25 GHz
TX-RX isolation on antenna level		–	35	–	dB	@ Freq = 61.25 GHz

2 SPI interface

2.1 SPI timing requirements

The BGT60LTR11AIP is configured using a 4-wire SPI. It is used to configure the internal blocks of the BGT60LTR11AIP chip registers. The main tasks are to set the mode of operation of the TX and/or RX chain and the baseband section. Communication with an external microcontroller is possible through the four dedicated pins SPIDI, SPIDO, SPICS and SPICLK. [Figure 1](#) demonstrates how the timing of the SPI behaves. The “working edge” is the rising edge of the clock SPICLK. The master application processor presents data for BGT60LTR11AIP at the falling edge on SPIDI, while BGT60LTR11AIP samples data at the rising edge. Read data is presented for the master on the rising edge on SPIDO. Asynchronous reset (SPIRSTN) must be de-asserted at least 10 ns before the falling edge of SPICLK. Refer to the application note AN625 for all details related to the SPI registers to control the MMIC.

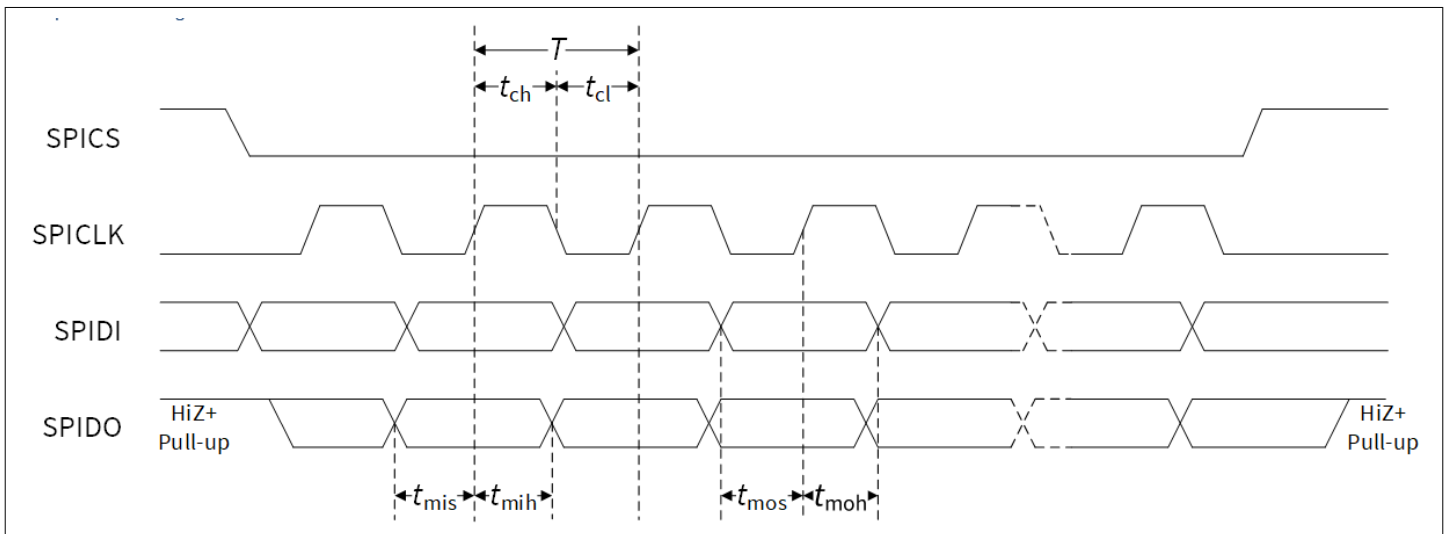


Figure 1 SPI timing diagram

Table 8 SPI timing requirements

Parameter	Symbol	Values			Unit	Note or Test Condition
		Min.	Typ.	Max.		
SPI clock period	T	20	–	–	ns	50 MHz, with <1% clock jitter
Clock high time	t_{ch}	9	–	–	ns	
Clock low time	t_{cl}	9	–	–	ns	
Setup time SPIDI	t_{mos}	5	–	–	ns	
Hold time SPIDI	t_{moh}	5	–	–	ns	
Setup time SPIDO	t_{mis}	5	–	–	ns	
Hold time SPIDO	t_{mih}	4	–	–	ns	

3 Block diagram and pin description

3.1 Block diagram

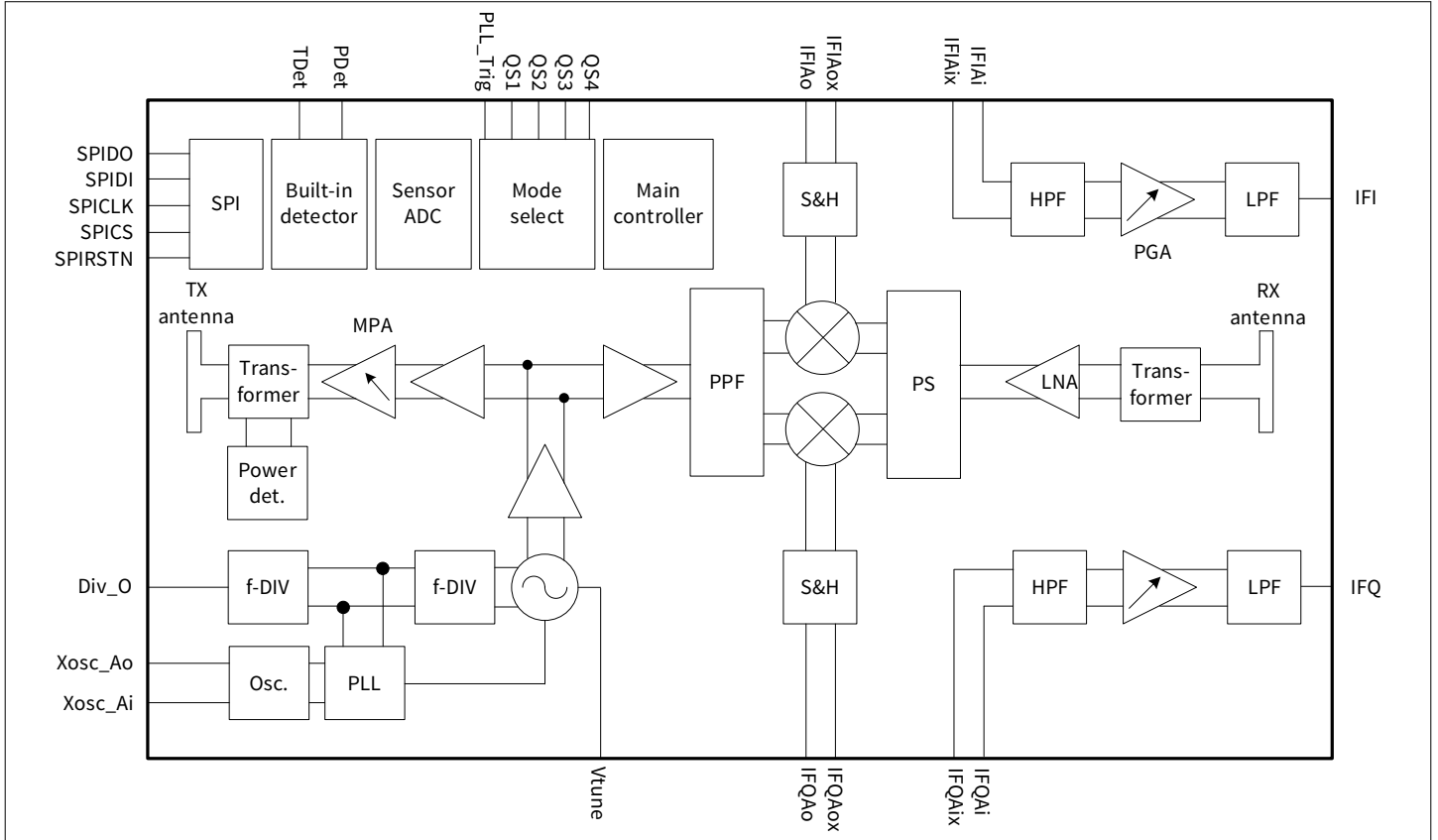


Figure 2 BGT60LTR11AIP block diagram

3.2 Pin out

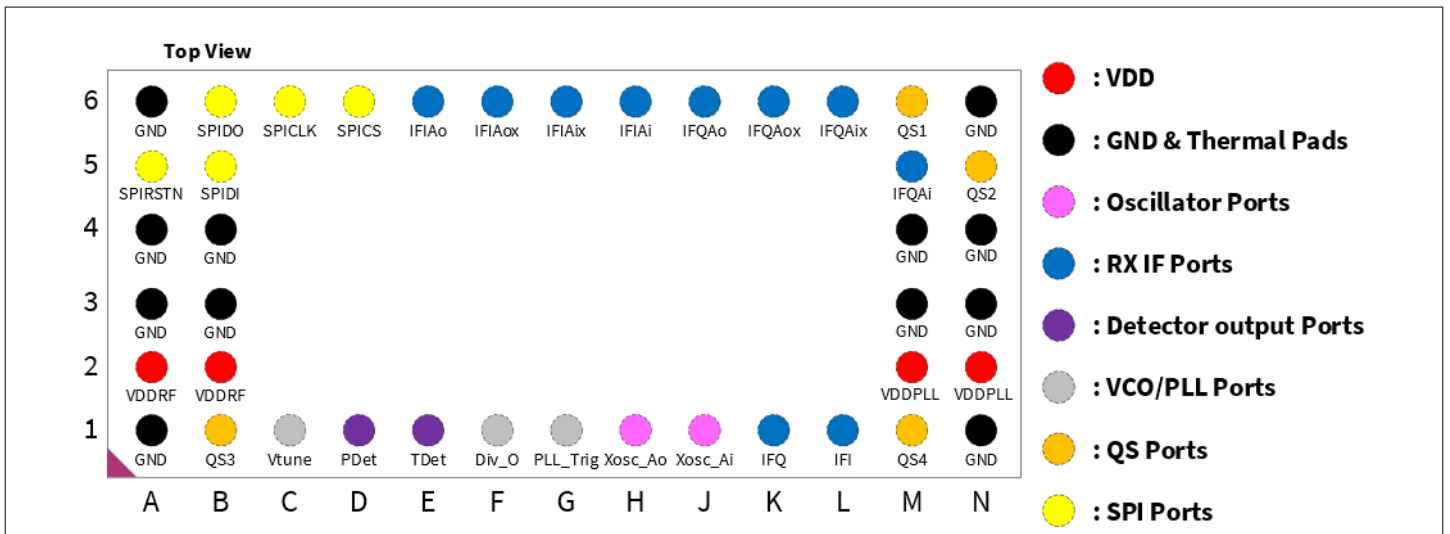


Figure 3 BGT60LTR11AIP pin out (top view)

3.3 Pin definition and function

Table 9 Pin definition and function

Pin number	Name	Function
A1, N1, A3, B3, M3, N3, A4, B4, M4, N4, A6, N6	GND	Ground
A2, B2	VDDRF	DC supply of 1.5 V to internal RF circuitry
M2, N2	VDDPLL	DC supply of 1.5 V to internal PLL circuitry
M6	QS1	Quad state input 1 – voltage value
N5	QS2	Quad state input 2 or analog input to configure detector threshold
B1	QS3	Quad state input 3 or analog input to configure detector hold time
M1	QS4	Quad state input 4
A5	SPIRSTN	SPI reset, active low
B5	SPIDI	SPI data in
B6	SPIDO	SPI data out
C6	SPICLK	SPI clock
D6	SPICS	SPI chip select, active low
E6, F6	IFIAo, IFIAox	Complementary in phase down converter IF output
J6, K6	IFQAo, IFQAox	Complementary quadrature phase down converter IF output
G6, H6	IFIAix, IFIAi	Analog IF input PGA – complementary in phase
L6, M5	IFQAix, IFQAI	Analog IF input PGA – complementary quadrature phase
K1	IFQ	ABB output – Q Channel
L1	IFI	ABB output – I Channel
C1	Vtune	VCO tuning voltage
D1	PDet	Detector output – direction of movement
E1	TDet	Detector output – motion
F1	Div_O	Frequency divider output
G1	PLL_Trig	“Advance mode” and “Basic mode” switch
H1	Xosc_Ao	Internal oscillator quartz node
J1	Xosc_Ai	Internal oscillator quartz node

4 Package dimensions and footprint

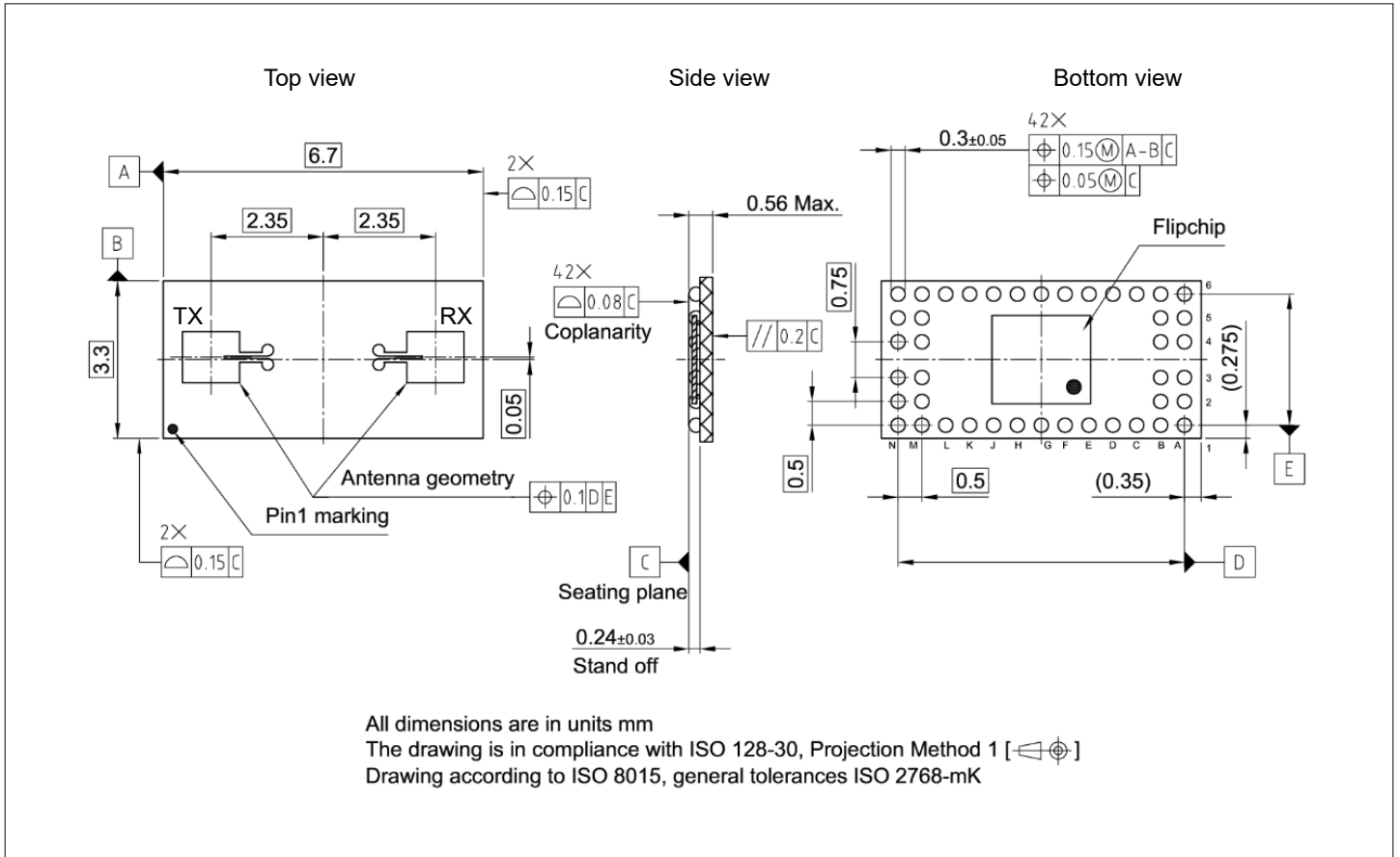


Figure 4 Package outline. Top, side and bottom view of PG-UF2BGA-42-1

Revision history

Document version	Date of release	Description of changes
V2.40	2021-10-11	Preliminary release
V2.50	2021-11-05	Initial release
V2.60	2022-08-01	Supported BGT60LTR11SAIP down-specified MMIC version
V2.61	2024-10-18	Updated Figure 4 to swap the labels of TX/RX antennas

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